

Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-02305 <i>W/ Komrad et al</i> APPLICANT: <i>Ray et al.</i>	SERIAL NO. 09/957,468 GROUP: 2852 <i>2877</i>
	FILING DATE: September 20, 2001	

U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HP</i>	D28	2002/0149782	10/2002	Raymond	<u> </u>	<u> </u>	
<i>HP</i>	D29	2002/0158193	10/2002	Sezginer et al.	<u> </u>	<u> </u>	
<i>HP</i>	D30	2002/0192577	12/2002	Fay et al.	<u> </u>	<u> </u>	

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
<i>HP</i>	D31	02/15238	2/2002	WO	<u> </u>	<u> </u>	
<i>HP</i>	D32	02/25723	3/2002	WO	<u> </u>	<u> </u>	
<i>HP</i>	D33	02/069390	9/2002	WO	<u> </u>	<u> </u>	

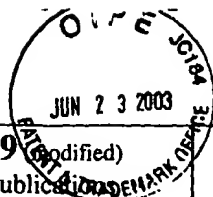
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>HP</i>	D34	McNeil et al., "Scatterometry Applied to Microelectronics Processing," Microlithography World, November/December 1992, pp. 16-22.
<i>HP</i>	D35	Raymond et al., "Metrology of subwavelength photoresist gratings using optical scatterometry," J. Vac. Sci. Technol. B 13(4), Jul/Aug 1995, pp. 1484-1495.
<i>HP</i>	D36	Wittekoek et al., "In-process Image Detecting Technique for Determination of Overlay, and Image Quality for ASM-L Wafer Stepper," SPIE Vol. 1674 Optical/Laser Microlithography V (1992), pp. 594-608.

EXAMINER: *HP*

DATE CONSIDERED: *7/28/04*

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.



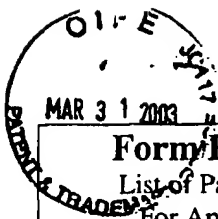
Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-02305 APPLICANT: <i>Intel</i> <i>Intel</i> <i>Intel</i> FILING DATE: September 20, 2001	SERIAL NO. 09/957,468 GROUP: 2862 2877
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U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
HP	E1	5,438,413	8/1995	Mazor et al.			
HP	E2	5,574,278	11/1996	Poirier			
HP	E3	5,703,692	12/1997	McNeil et al.			
HP	E4	5,798,529	8/1998	Wagner			
HP	E5	5,923,423	7/1999	Sawatari et al.			
HP	E6	5,963,314	10/1999	Worster et al.			
HP	E7	6,052,188	4/2000	Fluckiger et al.			
HP	E8	6,097,205	8/2000	Liberman et al.			
HP	E9	6,157,032	12/2000	Into			
HP	E10	6,166,801	12/2000	Dishon et al.			
HP	E11	6,174,743	1/2001	Pangrle et al.			
HP	E12	6,175,421	1/2001	Fuchs et al.			
HP	E13	6,188,478	2/2001	Fuchs et al.			
HP	E14	6,191,846	2/2001	Opsal et al.			
HP	E15	6,250,143	6/2001	Bindell et al.			
HP	E16	6,258,610	7/2001	Blatchford et al.			
HP	E17	6,266,144	7/2001	Li			
HP	E18	6,320,666	11/2001	Opsal et al.			
HP	E19	US 2001/0052257	12/2001	Magerle			
HP	E20	US 2002/0017619	2/2002	Hirose et al.			
HP	E21	6,383,824	5/2002	Lensing			
HP	E22	6,408,048	6/2002	Opsal et al.			
HP	E23	6,451,621	9/2002	Rangarajan et al.			
HP	E24	6,452,685	9/2002	Opsal et al.			
HP	E25	6,462,817	10/2002	Strocchia-Rivera			

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Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-02305 <i>Nikornukhal et al</i> APPLICANT: <i>Levy et al.</i> FILING DATE: September 20, 2001	SERIAL NO. 09/957,468 GROUP: 287 2877
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U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HP</i>	D1	4631416	12/1986	Trutna, Jr.	↑	↑	
<i>HP</i>	D2	5114235	5/1992	Suda et al.			
↑	D3	5182455	1/1993	Muraki			
	D4	5182610	1/1993	Shibata			
	D5	5189494	2/1993	Muraki			
	D6	5316984	5/1994	Leourx			
	D7	5327221	7/1994	Saitoh et al.			
	D8	5340992	8/1994	Matsugu et al.			
	D9	5414514	5/1995	Smith et al.			
	D10	5666196	9/1997	Ishii et al.			
	D11	5783342	7/1998	Yamashita et al.			
	D12	5801390	9/1998	Shiraishi			
	D13	6046094	4/2000	Jost et al.			
	D14	6077756	6/2000	Lin et al.			
	D15	6079256	6/2000	Bareket			
	D16	6128089	10/2000	Ausschnitt et al.			
	D17	6153886	11/2000	Hagiwara et al.			
	D18	6177330	1/2001	Yasuda			
	D19	6255189	7/2001	Muller et al.			
	D20	6301011	10/2001	Fung et al.			
	D21	6388253	5/2002	Su			
	D22	6421124	7/2002	Matsumoto et al.			
	D23	6462818	10/2002	Bareket			
	D24	6476920	11/2002	Scheiner et al.			
	D25	6486492	11/2002	Su			
<i>HP</i>	D26	6486954	11/2002	Mieher et al.			
<i>HP</i>	D27	2002/0018217	2/2002	Weber-Grabau et al.			

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